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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet **1** of **8**

### Complete if Known

Application Number	10/600,721
Filing Date	6/20/2003
First Named Inventor	Bickford, Randall L.
Group Art Unit	2121
Examiner Name	Not yet Assigned
Attorney Docket Number	23406-cip

### U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code <sup>2</sup> (if known)			
	1	4,295,128		Hashemian et al.	10-13-1981	
	2	4,478,783		Broadwater	10-23-1984	
	3	4,761,748		Le Rat et al.	08-02-1988	
	4	4,937,763		Mott	06-26-1990	
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	6	5,009,833		Takeuchi et al.	04-23-1991	
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	9	5,381,140		Kuroda, et al.	01-10-1995	
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### FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)				

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Sheet 2 of 8

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Ramc A Patel

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		Application Number	10/600,721		
		Filing Date	6/20/2003		
		First Named Inventor	Bickford, Randall L.		
		Group Art Unit	2121		
		Examiner Name	Not yet Assigned		
Sheet	5	of	8	Attorney Docket Number	23406-cip

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
R.P.	62	BICKFORD, R.L., Phase Partitioning the Multivariate State Estimation Technique (MSET) Process for Improved Parameter Estimation Performance and Processing Speed, New Technology Report, January 13, 2000, Printed in USA by Expert Microsystems, Inc.	
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Examiner Signature	<i>Ramesh Patel</i>	Date Considered	1/30/05
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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)		Application Number	10/600,721
		Filing Date	6/20/2003
		First Named Inventor	Bickford, Randall L.
		Group Art Unit	2121
		Examiner Name	Not yet Assigned
Sheet 6	of 8	Attorney Docket Number	23406-clp

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
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Examiner Signature	<i>Ramsey Patel</i>	Date Considered	1/30/05
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Sheet	7	of	8	Attorney Docket Number	23406-cip

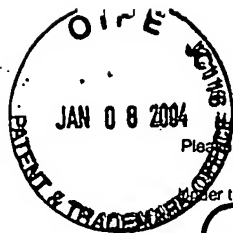
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Examiner Signature	<i>Randy Patel</i>	Date Considered	1/30/05
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